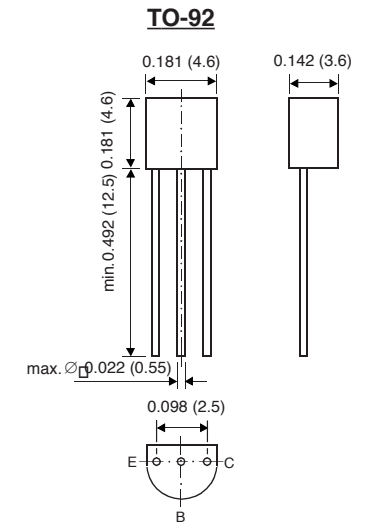


2N3906

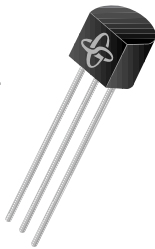
SMALL SIGNAL TRANSISTORS (PNP)



Dimensions in inches and (millimeters)

FEATURES

- ◆ PNP Silicon Epitaxial Planar Transistor for switching and amplifier applications.
- ◆ As complementary type, the NPN transistor 2N3904 is recommended.
- ◆ On special request, this transistor is also manufactured in the pin configuration TO-18.
- ◆ This transistor is also available in the SOT-23 case with the type designation MMBT3906.



MECHANICAL DATA

Case: TO-92 Plastic Package
Weight: approx. 0.18g

MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

Ratings at 25°C ambient temperature unless otherwise specified

	SYMBOL	VALUE	UNIT
Collector-Base Voltage	$-V_{CBO}$	40	Volts
Collector-Emitter Voltage	$-V_{CEO}$	40	Volts
Emitter-Base Voltage	$-V_{EBO}$	5.0	Volts
Collector Current	$-I_C$	200	mA
Power Dissipation at $T_A = 25^{\circ}\text{C}$ at $T_C = 25^{\circ}\text{C}$	P_{tot}	625 1.5	mW Watts
Thermal Resistance Junction to Ambient Air	$R_{\theta JA}$	250 ⁽¹⁾	$^{\circ}\text{C/W}$
Junction Temperature	T_j	150	$^{\circ}\text{C}$
Storage Temperature Range	T_S	- 65 to +150	$^{\circ}\text{C}$

NOTES:
(1) Valid provided that leads are kept at ambient temperature.

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ELECTRICAL CHARACTERISTICS

Ratings at 25°C ambient temperature unless otherwise specified

	SYMBOL	MIN.	MAX.	UNIT
Collector-Base Breakdown Voltage at $-I_C = 10 \mu A$, $I_E = 0$	$-V_{(BR)CBO}$	40	—	Volts
Collector-Emitter Breakdown Voltage at $-I_C = 1 \text{ mA}$, $I_B = 0$	$-V_{(BR)CEO}$	40	—	Volts
Emitter-Base Breakdown Voltage at $-I_E = 10 \mu A$, $I_C = 0$	$-V_{(BR)EBO}$	5	—	Volts
Collector Saturation Voltage at $-I_C = 10 \text{ mA}$, $-I_B = 1 \text{ mA}$ at $-I_C = 50 \text{ mA}$, $-I_B = 5 \text{ mA}$	$-V_{CEsat}$ $-V_{CEsat}$	— —	0.25 0.4	Volts Volts
Base Saturation Voltage at $-I_C = 10 \text{ mA}$, $-I_B = 1 \text{ mA}$ at $-I_C = 50 \text{ mA}$, $-I_B = 5 \text{ mA}$	$-V_{BEsat}$ $-V_{BEsat}$	— —	0.85 0.95	Volts Volts
Collector-Emitter Cutoff Current at $-V_{EB} = 3 \text{ V}$, $-V_{CE} = 30 \text{ V}$	$-I_{CEV}$	—	50	nA
Emitter-Base Cutoff Current at $-V_{EB} = 3 \text{ V}$, $-V_{CE} = 30 \text{ V}$	$-I_{EBV}$	—	50	nA
DC Current Gain at $-V_{CE} = 1 \text{ V}$, $-I_C = 0.1 \text{ mA}$ at $-V_{CE} = 1 \text{ V}$, $-I_C = 1 \text{ mA}$ at $-V_{CE} = 1 \text{ V}$, $-I_C = 10 \text{ mA}$ at $-V_{CE} = 1 \text{ V}$, $-I_C = 50 \text{ mA}$ at $-V_{CE} = 1 \text{ V}$, $-I_C = 100 \text{ mA}$	h_{FE} h_{FE} h_{FE} h_{FE} h_{FE}	60 80 100 60 30	— — 300 — —	— — — — —
Input Impedance at $-V_{CE} = 10 \text{ V}$, $-I_C = 1 \text{ mA}$, $f = 1 \text{ kHz}$	h_{ie}	1	10	k Ω
Voltage Feedback Ratio at $-V_{CE} = 10 \text{ V}$, $-I_C = 1 \text{ mA}$, $f = 1 \text{ kHz}$	h_{re}	$0.5 \cdot 10^{-4}$	$8 \cdot 10^{-4}$	—
Gain-Bandwidth Product at $-V_{CE} = 20 \text{ V}$, $-I_C = 10 \text{ mA}$, $f = 100 \text{ MHz}$	f_T	250	—	MHz
Collector-Base Capacitance at $-V_{CB} = 5 \text{ V}$, $f = 100 \text{ kHz}$	C_{CBO}	—	4.5	pF
Emitter-Base Capacitance at $-V_{EB} = 0.5 \text{ V}$, $f = 100 \text{ kHz}$	C_{EBO}	—	10	pF

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ELECTRICAL CHARACTERISTICS

Ratings at 25°C ambient temperature unless otherwise specified

	SYMBOL	MIN.	MAX.	UNIT
Small Signal Current Gain at $-V_{CE} = 10\text{ V}$, $-I_C = 1\text{ mA}$, $f = 1\text{ kHz}$	h_{fe}	100	400	—
Output Admittance at $-V_{CE} = 1\text{ V}$, $-I_C = 1\text{ mA}$, $f = 1\text{ kHz}$	h_{oe}	1	40	μS
Noise Figure at $-V_{CE} = 5\text{ V}$, $-I_C = 100\text{ }\mu\text{A}$, $R_G = 1\text{ k}\Omega$, $f = 10 \dots 15000\text{ Hz}$	NF	—	4	dB
Delay Time (see Fig. 1) at $-I_{B1} = 1\text{ mA}$, $-I_C = 10\text{ mA}$	t_d	—	35	ns
Rise Time (see Fig. 1) at $-I_{B1} = 1\text{ mA}$, $-I_C = 10\text{ mA}$	t_r	—	35	ns
Storage Time (see Fig. 2) at $I_{B1} = -I_{B2} = 1\text{ mA}$, $-I_C = 10\text{ mA}$	t_s	—	225	ns
Fall Time (see Fig. 2) at $I_{B1} = -I_{B2} = 1\text{ mA}$, $-I_C = 10\text{ mA}$	t_f	—	75	ns

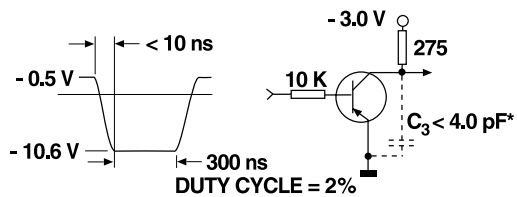


Fig. 1: Test circuit for delay and rise time

* total shunt capacitance of test jig and connectors

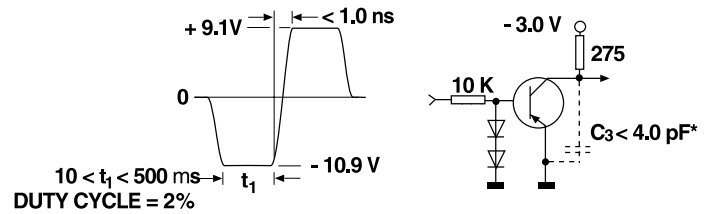


Fig. 2: Test circuit for storage and fall time

* total shunt capacitance of test jig and connectors